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HP	AR	Bergano, et al; "Margins Measurements in Optical Amplifier Systems"; IEEE Photonics
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HP	AS	Ohteru, et al; "Optical Signal Quality Monitor Using Direct Q-Factor Measurement"; IEEE Photonics Technology Letters; Vol. 11, No. 10; Pages 1307-1309; October 1999.
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SP02-274 PTO-1449 (MODIFIED) ATTORNEY DOCKET NO. SERIAL NO. LIST OF PATENTS AND SP02-274 10/677450 **PUBLICATIONS** FOR APPLICANTS INFORMATION **DISCLOSURE STATEMENT** APPLICANT DOWNIE JOHN D, et al. 2613 FILING DATE 10/2/2003 GROUP: 2877 REFERENCE DESIGNATION U.S. PATENT DOCUMENTS Filing Date Examiner **Document Number** Date Name Class Subif Approp. Initial Class AA ABAC AD AE AF AG AH ΑI AJ AK FOREIGN PATENT DOCUMENTS

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НР	AR	Downie et al.; "Performance monitoring of optical networks with synchronous and asynchronous sampling"; Optical Fiber Communication Conference; March 17-22, 2001; Volume 54
HP	AS	Li, Jinhui et al; "Q factor on-line detection in optical fiber lans"; International Journal of Infarared and Millimeter Waves; Vol. 22, No. 5, 2001; pages 715-722.
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	T	Bergano, et al.; "Margin Measurements in Optical Amplifier Systems"; IEEE Photonics Technology Letters, Vol. 5, No. 3; March 1993; pages 304-306.										
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